	SE	101	BIL '							
FORM TO-	14494	Pettent and Trac	mmerce lemark	ATTORNEY DOCKET NO.		SERIAL NO. 09/823,196				
INFORMAT	.     . ION DI:	SCOOSURE STA		APPLICANT Thomas H. Baum, et al.						
(use several sheets if necessary)				FILING DATE	GROUP					
				March 30, 2001		TBA				
			U.S. 1	PATENT DOCUMENTS	<del> </del>		777 TVO	D 4 (CE)		
EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING IF APPRO			
CR	AA	6,159,855	12/12/00	B. Vaartstra						
5 L	AB	6,013,553	1/11/00	R. Wallace, et al.						
22	AC	5,820,678	10/13/98	Hubert, et al.						
EK	AD	5,204,314	4/20/93	Peter S. Kirlin, et al.						
EK	AE	5,536,323	7/16/96	Peter S. Kirlin, et al.						
	AF	09/414,133		Thomas H. Baum, et al.			_10/7/99			
EK	AG	6,015,917	1/18/2000	G. Bhandari, et al.						
Ex	AH	5,972,430	10/26/99	Frank DiMeo, Jr.						
El-	AI	5,919,522	7/6/99	Thomas H. Baum, et al.	_	_	-			
ER	AJ	6,110,529	8/28/2000	Robin A. Gardiner, et al.	-	<del>-</del> .				
ER	AK	5,820,664	10/13/98	Robin A. Gardiner, et al.						
R EIL	AL	5,536,323	7/16/96	Peter S. Kirlin, et al.	1-					
	AM	07/927,134		Peter S. Kirlin, et al.			8/7/92			
Ex	AN	5,453,494	9/26/95	Peter S. Kirlin, et al.						
EK_	AO	5,280,012	1/18/94	Peter S. Kirlin, et al.						
	AP	07/615,303		Duncan W. Brown			11/19/90			
EL	AQ	5,225,561	7/6/93	Peter S. Kirlin, et al.						
	AR-	07/549,389					7/6/90	_		
9K	AS	5,876,503	3/2/99	Jeffrey F. Roeder et al.	_	_				
	<u> </u>		FOREIG	GN PATENT DOCUMENTS	S					
		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLAS S	TRANSL YES	ATION NO		
							X (abstrac t only)			
		OTHER DOCU	MENTS (Includ	ling Author, Title, Journal-I	Date, Page I	Number, Etc.)				
		<u> </u>						_		
				Continue on Page 2						
THE ALL STREET				Continue on 1 age 2	DATE	ONGIDEDEL				
EXAMINE	EXAMINER CIPLED					DATE CONSIDERED  7/1/02.				
EXAMINE	R: Initia	l if citation consi	dered, whether o	or not citation is in conforman	ce with MPI	EP § 609; Dra	w line throu	gh		

2

FORM PTO-1449		US Dept. of Commerce Patent and Trademark Office		ATTORNEY DOCKET NO		SERIAL NO. 09/823,196						
INFORMAT	IOND	SCLOSURE STA	TEMENT	APPLICANT Thomas H. Baum, et al.	1 7 2801	11 1						
use several sheets in necessary ELLED				FILING DATE	TRADENARY	GROUP TBA						
(	JUL ~ 1	I BOOK BY		March 30, 2001	MADE	IBA						
U.S. PATENT DOCUMENTS												
EXAMINER INITIAL	EMET	FADE UMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING IF APPRO					
EK	BA	5,976,991	12/2/99	R. Laxman, et al.		_						
EK	BB	6,177,135	1/23/01	Frank S. Hintermaier, et al.				<u>.</u>				
EL	BC	4,895,709	1/23/90	Richard M. Laine	_	~						
Eir	BD	5,139,825	8/18/92	Gordon, et al.		_						
EK	BE	5,003,092	3/26/91	Orville T. Beachley, Jr.	(							
CK	BF	5,178,911	1/12/93	Roy G. Gordon, et al.		(						
EK	BG	6,060,406	5/9/00	Glen B. Alers, et al.		_						
EK	ВН	5,924,012	7/13/99	Brian A. Vaartstra	_							
Ek	BI	6,020,243	2/1/00	Robert M Wallace, et al.								
FOREIGN PATENT DOCUMENTS												
		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLAS S	TRANSL YES	NO NO				
					e ·		X (abstrac t only)					
		OTHER DOCUM	IENTS (Includ	ing Author, Title, Journal-Da	ate, Page N	lumber, Etc.)	01 677	<del></del>				
Ex	BJ			nia Thin Films by Direct Liquid ol. 4, 1998, pp. 46-49.	Injection	Using a New (	Class of Zir	conium				
	DV DC Bradley et al. "Metalorganic Compounds Containing Metal-Nitrogen Bonds: Part I Some											
	/BL	Dialkyamino De	al "Metalorgan	ic Compounds Containing Me	tal-Nitroge	n Bonds: Part	III. Dialky	lamino				
EK	Compounds of Tantalum", Canadian J. Chem., 40, 1355 (1962)											
EX	BM S. Giles, et al., "Deposition of (Ti,Al)N thin films by organometallic chemical vapor deposition: thermodynamic predictions and experimental results", Elsevier Science, SA, Surface and Coatings											
		Technology, 94-	95 (1997), pgs. 2	285-290.								
Ex	BN	Kozoh Sugiyama, et al., "Low Temperature Deposition of Metal Nitrides by Thermal Decomposition of										
	The state of the s											
EK	Ed., 5, (2), 247 (1966).											
Continue on Page												
EXAMINE	₹		`		DATE CONSIDERED							
Ex Kill					7/1/02							
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through												
citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.												